Search Notes



Apr	plica	tion	/Con	trol	No.

Maikhanh Nguyen

10/606,547 Examiner

Applicant(s)/Patent under Reexamination

WASON, JAMES R. Art Unit

2176

	SEAR	CHED	
Class	Subclass	Date	Examiner
715	531	3/25/2006) MK
	513, 529	3/25/2006	· MK
707	102	3/25/2006	MK
719	316	3/25/2006	MK
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor Name Search	3/25/2006	MK	
West Search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/25/2006	MK	
West Search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/31/2006	мк	
Consulted with Primary William Bashore	3/31/2006	МК	
NPL (IEEE)	3/31/2006	MK	
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